

**Search Notes (continued)**

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Examiner

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Applicant(s)/Patent under  
Reexamination

HONKEN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
375	260	5/29/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	5/29/2007	SZ
Kazuyuki Oka Yokoham	5/29/2007	SZ
(375/260 375/354 375/355 375356 375/357).ccls.	5/29/2007	SZ
(370/470 370/345).ccls.	5/29/2007	SZ
(IEEE Xplore Database ( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	5/29/2007	SZ
Consulted with SPE Rafael Perez- Gutierrez.	5/29/2007	SZ